### **Description**

### **N-channel Enhancement Mode Power MOSFET**

#### **Features**

• 60V, 50A

 $R_{DS(ON)} < 15m\Omega @ V_{GS} = 10V$  $R_{DS(ON)} < 21m\Omega @ V_{GS} = 4.5V$ 

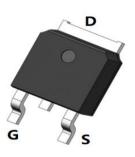
- Advanced Trench Technology
- Excellent R<sub>DS(ON)</sub> and Low Gate Charge

#### **Applications**

- Load Switch
- PWM Application
- Power Management

100% UIS TESTED! 100% ΔVds TESTED!

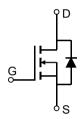








**Marking and Pin Assignment** 



**Schematic Diagram** 

#### **Package Marking and Ordering Information**

Device Marking	Device	Outline	Package	Reel Size	Reel(pcs)	Per Carton (pcs)
CRMKTL0617A	CRMKTL0617A	TAPING	TO-252-3L	13"	2500	25000

#### Absolute Maximum Ratings (@ T<sub>C</sub> = 25°C unless otherwise specified)

Symbol	Parameter		Value	Units	
V <sub>DS</sub>	Drain-to-Source Voltage		60	V	
$V_{GS}$	Gate-to-Source Voltage		±20	V	
	Continuous Drain Current	$T_C = 25^{\circ}C$	50	А	
I <sub>D</sub>		T <sub>C</sub> = 100°C	33		
I <sub>DM</sub>	Pulsed Drain Current (1)		200	А	
E <sub>AS</sub>	Single Pulsed Avalanche Energy <sup>(2)</sup>		81	mJ	
$P_{D}$	Power Dissipation	T <sub>C</sub> = 25°C	62.5	W	
$R_{\theta JC}$	Thermal Resistance, Junction to Case		2.0	°C/W	
$T_J$ , $T_{STG}$	Junction & Storage Temperature R	ange	-55 to 150	°C	

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#### **Electrical Characteristics** (T<sub>J</sub> = 25°C unless otherwise specified)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit		
Off Characteristics								
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	60	-	-	V		
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 60V, V_{GS} = 0V$	-	-	1.0	μА		
I <sub>GSS</sub>	Gate-Body Leakage Current	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	±100	nA		
On Cha	racteristics							
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1.0	1.6	2.5	V		
Б	(0)	$V_{GS} = 10V, I_D = 30A$	-	12.0	15.0	mΩ		
$R_{DS(ON)}$		$V_{GS} = 4.5V, I_D = 20A$	-	16.0	21.0	mΩ		
Dynamic Characteristics								
C <sub>iss</sub>	Input Capacitance		- (	2030	-	pF		
C <sub>oss</sub>	Output Capacitance	$V_{GS} = 0V, V_{DS} = 25V,$ f = 1MHz	-1	133	-	pF		
$C_{rss}$	Reverse Transfer Capacitance	1 - 11/11/12	-	122	-	pF		
$Q_g$	Total Gate Charge	V 01 40V	_	45	-	nC		
$Q_{gs}$	Gate Source Charge	$V_{GS} = 0 \text{ to } 10V$ $V_{DS} = 30V, I_{D} = 30A$	<b>O</b> -	8	-	nC		
$Q_{gd}$	Gate Drain("Miller") Charge	V <sub>DS</sub> = 30 V, I <sub>D</sub> = 30A	-	11	-	nC		
Switchi	ing Characteristics							
t <sub>d(on)</sub>	Turn-On DelayTime	( )	-	11	-	ns		
t <sub>r</sub>	Turn-On Rise Time	$V_{GS} = 10V, V_{DD} = 30V$	-	79	-	ns		
$t_{d(off)}$	Turn-Off DelayTime	$I_{D}$ = 30A, $R_{GEN}$ = 1.8 $\Omega$	-	33	-	ns		
t <sub>f</sub>	Turn-Off Fall Time		-	107	-	ns		
Drain-S	Source Diode Characteristics and N	lax Ratings						
Is	Maximum Continuous Drain to Source Diod	e Forward Current	-	-	50	Α		
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current		-	-	200	А		
V <sub>SD</sub>	Drain to Source Diode Forward Voltage	$V_{GS} = 0V, I_{S} = 30A$	-	-	1.2	V		

Notes:

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<sup>1.</sup> Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.

<sup>2.</sup>  $E_{AS}$  condition: Starting  $T_J$ =25C,  $V_{DD}$ =30V,  $V_G$ =10V,  $R_G$ =25ohm, L=0.5mH,  $I_{AS}$ =18A

<sup>3.</sup> Pulse Test: Pulse Width  $\leq$  300  $\mu$ s, Duty Cycle  $\leq$  0.5%.

### **Typical Performance Characteristics**

Figure 1: Output Characteristics

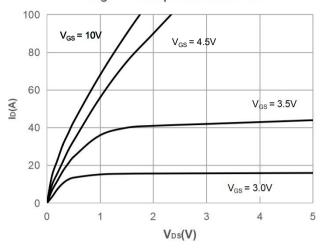


Figure 2: Typical Transfer Characteristics

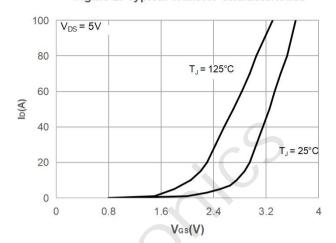


Figure 3: On-resistance vs. Drain Current

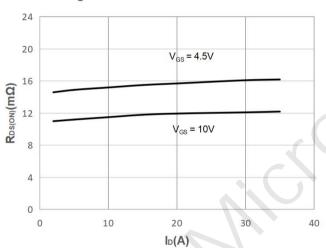


Figure 4: Body Diode Characteristics

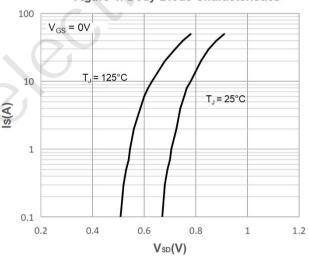


Figure 5: Gate Charge Characteristics

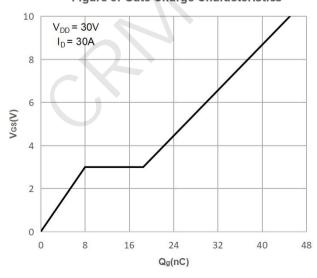
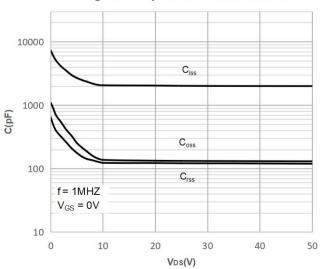


Figure 6: Capacitance Characteristics



### **Typical Performance Characteristics**

Figure 7: Normalized Breakdown voltage vs. Junction Temperature

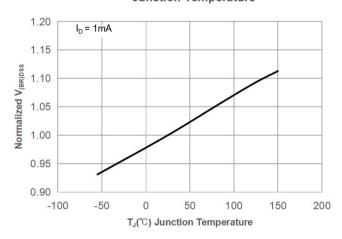


Figure 9: Maximum Safe Operating Area

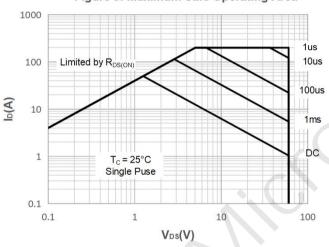


Figure 11: Normalized Maximum Transient Thermal Impedance

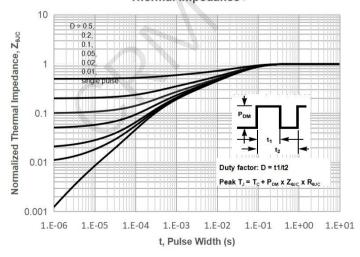


Figure 8: Normalized on Resistance vs. Junction Temperature

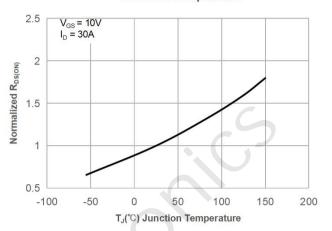


Figure 10: Maximum Continuous Drian Current vs. Case Temperature

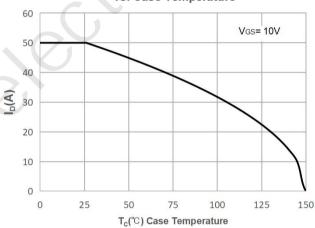
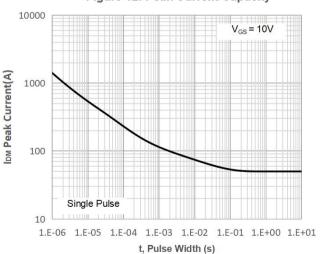


Figure 12: Peak Current Capacity





#### **Test Circuit**

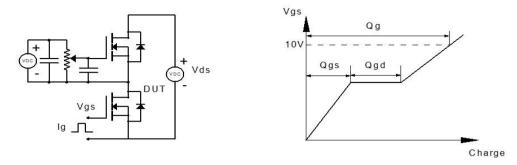


Figure 1: Gate Charge Test Circuit & Waveform

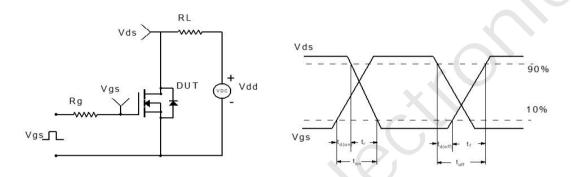


Figure 2: Resistive Switching Test Circuit & Waveform

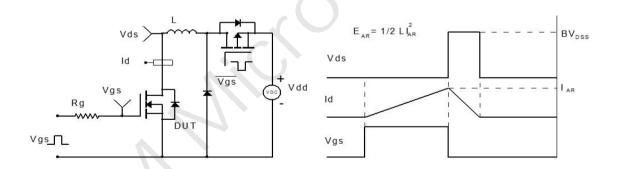


Figure 3: Unclamped Inductive Switching Test Circuit& Waveform

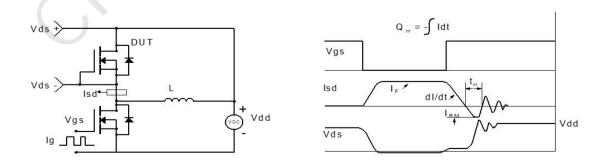
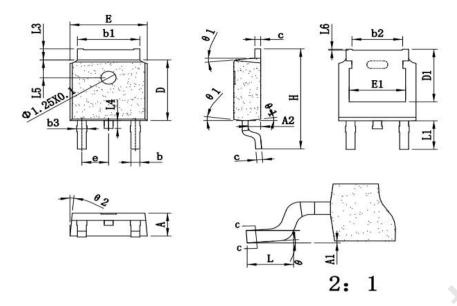


Figure 4: Diode Recovery Test Circuit & Waveform



### Package Mechanical Data(TO-252-3L)



SYMBOL	mm				
	MIN	NOM	MAX		
*A	2. 20	2. 30	2. 38		
*A1	0.00	1 <del></del>	0. 15		
* A2	0. 90	1.00	1. 10		
<b>*</b> b	0. 72	0. 78	0. 85		
b1	5. 23	5. 33	5. 46		
ь2	4. 05	4. 20	4. 35		
<b>*</b> b3	0. 78	0. 85	0. 90		
*c	0. 47	0. 52	0. 55		
r≱ D	6. 00	6. 10	6. 20		
D1	5. 40REF				
≠E	6. 50	6. 60	6. 70		
E1	4. 70	4. 83	4. 92		
*e	2. 286BSC				
<b>*</b> H	9. 90	10. 10	10. 20		
*L	1. 40	1. 55	1. 70		
L1	2. 90REF				
L3	0. 90	_	1. 20		
L4	0. 75	0. 85	0. 95		
L5	1. 70	1.80	1. 90		
L6	0.00	0.06	0. 12		
*0	0*	72	5*		
<b>81</b>	5°	7°	9°		
62	5*	7*	9.		

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